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Product Change Notification - KSRA-03AYHE005 (Convert To PDF)

| Date: | 07 May 2018 |
|-----------------------|---|
| Product Category: | 8-bit PIC Microcontrollers; Capacitive Touch Sensors |
| Affected CPNs: | |
| Notification subject: | CCB 3296 Initial PCN: Qualification of gold (Au) bond wire as secondary wire material for |
| | selected Atmel products available in 44L TQFP (10x10x1.0mm) package at MTAI Assembly |
| | site |
| Notification text: | PCN Status: Initial notification |
| | PCN Type: Manufacturing Change |

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of gold (Au) bond wire as secondary wire material for selected Atmel products available in 44L TQFP (10x10x1.0mm) package at MTAI Assembly site

Pre Change:

Using palladium coated copper wire with gold flash (CuPdAu) bond wire

Post Change:

Using palladium coated copper wire with gold flash (CuPdAu) or gold (Au) bond wire

Pre and Post Change Summary:

| | Pre Change | Post Change | | | |
|------------------------------|-------------------------------------|-------------------------------------|-------------------------------------|--|--|
| Assembly Site | Microchip Technology Thailand | Microchip Technology Thailand | Microchip Technology Thailand | | |
| | (HQ) / MTAI | (HQ) / MTAI | (HQ) / MTAI | | |
| Wire material | CuPdAu | CuPdAu | Au | | |
| Die attach material | 3280 | 3280 | 3280 | | |
| Molding compound material | G700HA | G700HA | G700HA | | |
| Lead frame material | Lead frame C7025 | | C7025 | | |

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve on-time delivery performance by qualifying gold (Au) bond wire for selected Atmel devices at MTAI assembly site.

Change Implementation Status:

In Progress

Estimated Qualification Completion Date:

May 2018

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Time Table Summary:

| | May2018 | | | | |
|-----------------------------|---------|----|----|----|----|
| Workweek | 18 | 19 | 20 | 21 | 22 |
| Initial PCN Issue Date | | Х | | | |
| Qual Report Availability | | | | | |
| Final PCN Issue Date | | | | | Х |

Method to Identify Change:

Traceability code

Qualification Plan:

Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History:

May 07, 2018: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN_KSRA-03AYHE005_Qual_Plan.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

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Affected Catalog Part Numbers (CPN)

AT42QT1481-AU AT42QT1481-AUR AT42QT2640-AU AT42QT2640-AUR ATMEGA1284-AU ATMEGA1284-AUR ATMEGA1284P-AU ATMEGA1284P-AUR ATMEGA16-16AU ATMEGA16-16AUA2 ATMEGA16-16AUR ATMEGA164A-AU ATMEGA164A-AUA2 ATMEGA164A-AUR ATMEGA164A-AURA2 ATMEGA164PA-AN ATMEGA164PA-ANR ATMEGA164PA-AU ATMEGA164PA-AUR ATMEGA164P-B15AZ ATMEGA16A-AU ATMEGA16A-AUA9 ATMEGA16A-AUR ATMEGA16A-AURA3 ATMEGA16A-AURA4 ATMEGA16A-AURA8 ATMEGA16L-8AU ATMEGA16L-8AUA7 ATMEGA16L-8AUR ATMEGA16L-8AURA1 ATMEGA16U4-AU ATMEGA16U4-AUR ATMEGA16U4RC-AU ATMEGA32-16AU ATMEGA32-16AUR ATMEGA324A-AU ATMEGA324A-AUR ATMEGA324A-AURA3 ATMEGA324PA-AN ATMEGA324PA-ANR ATMEGA324PA-AU ATMEGA324PA-AUA1 ATMEGA324PA-AUR ATMEGA324P-B15AZ ATMEGA32A-AN ATMEGA32A-ANR ATMEGA32A-AU

Date: Monday, May 07, 2018

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ATMEGA32A-AUR626 ATMEGA32A-AURA5 ATMEGA32A-AURA6 ATMEGA32A-AURA7 ATMEGA32L-8AU ATMEGA32L-8AUR ATMEGA32U4-AU ATMEGA32U4-AUR ATMEGA32U4RC-AU ATMEGA32U4RC-AUR ATMEGA644A-AU ATMEGA644A-AUR ATMEGA644PA-AN ATMEGA644PA-ANR ATMEGA644PA-AU ATMEGA644PA-AUR



QUALIFICATION PLAN SUMMARY

PCN#: KSRA-03AYHE005

Date: Mar 21, 2018

Qualification of gold (Au) bond wire as secondary wire material for selected Atmel products available in 44L TQFP (10x10x1.0mm) package at MTAI Assembly site Purpose: Qualification of gold (Au) bond wire as secondary wire material for selected Atmel products available in 44L TQFP (10x10x1.0mm) package at MTAI Assembly site

CCB No.: 3296

| | Assembly site | MTAI | | | | |
|----------------------------|-------------------|--------------------|--|--|--|--|
| Misc. | BD Number | BDM-001705 rev.A | | | | |
| | MP Code (MPC) | 354787T4XC01 | | | | |
| | Part Number (CPN) | ATMEGA644 | | | | |
| | Paddle size | 180x180 mils | | | | |
| | Material | C7025 | | | | |
| ne | Surface | Bare Cu on paddle | | | | |
| ran | Treatment | Roughening | | | | |
| Id-F | Process | Stamped | | | | |
| Lea | Lead-lock | No | | | | |
| | Part Number | 10104412 | | | | |
| | Lead Plating | Matte Tin | | | | |
| <u>Bond</u> <u>Wire</u> | Material Au | | | | | |
| <u> Die</u> tach | Part Number | 3280 | | | | |
| Att | Conductive | Yes | | | | |
| MC | Part Number | G700HA | | | | |
| | PKG Type | TQFP | | | | |
| PKG | Pin/Ball Count | 44 | | | | |
| | PKG width/size | 10x10 mm | | | | |
| Die | Die Thickness | 11 mils | | | | |
| | Die Size | 164.4 x 119.8 mils | | | | |
| | MSL | MSL1/260 | | | | |

| Test Name | Conditions | Sample Size | Min. Qty of Spares per Lot (should be properly marked) | Qty of Lots | Total Units | Fail Accept Qty | Est. Dur. Days | Test Site | Special Instructions |
|--|--|--|--|----------------|----------------|------------------|----------------------|-----------|--|
| Wire Bond Pull - WBP | Mil. Std. 883-2011 | 5 | 0 | 1 | 5 | 0 fails after TC | 5 | MTAI | 30 bonds from a min. 5 devices. |
| Wire Bond Shear - WBS | CDF-AEC-Q100-001 | 5 | 0 | 1 | 5 | | 5 | MTAI | 30 bonds from a min. 5 devices. |
| External Visual | Mil. Std. 883-2009/2010 | All devices prior to submission for qualification testing | 0 | 3 | ALL | 0 | 5 | MTAI | |
| HTSL (High Temp Storage Life) | +175 C for 504 hours or 150°C for 1008 hrs. Electrical test pre and post stress at +25C and hot temp. | 45 | 5 | 1 | 50 | 0 | 10 | MTAI | Must be in progress at time of package release to production, but completion is not required for release to production. |
| Preconditioning - Required for surface mount devices | +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec- STD-020E for package type; Electrical test pre and post stress at +25°C. | 231 | 15 | 3 | 738 | 0 | 15 | ΜΤΑΙ | Spares should be properly identified. 77 parts from each lot to be used for HAST, Autoclave, Temp Cycle test. |
| HAST | +130°C/85% RH for 96 hours. Electrical test pre and post stress at +25°C and hot temp. | 77 | 5 | 3 | 246 | 0 | 10 | MTAI | Spares should be properly identified. Use the parts which have gone through Pre- conditioning. |
| UHAST | +130°C/85% RH for 96hrs. Electrical test pre and post stress at +25°C | 77 | 5 | 3 | 246 | 0 | 10 | MTAI | Spares should be properly identified. Use the parts which have gone through Pre- conditioning. |
| Temp Cycle | -65°C to +150°C for 500 , 1000 cycles. Electrical test pre and post stress at hot temp; 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress. | 77 | 5 | 3 | 246 | 0 | 15 | MTAI | Spares should be properly identified. Use the parts which have gone through Pre- conditioning. |